

NI Solutions:
Semiconductor Test





Lowering the cost of test and improving time to market with a disruptive approach to semiconductor test.



The Traditional Approach is Not Scaling

The world around us is changing and technology is getting a lot smarter. A smartphone is far more than a phone. It is a super computer, a primary interface to the web, a social media device, a way to control a smart home, and so much more. As the devices we use get smarter, they become more software centric, and the semiconductor industry that is powering these smart devices is going through a transformation not only in how the ICs are designed and manufactured but also in how they are tested.

Regardless of the type of smart device, the business drivers are the same. IC makers must deliver more integrated functionality, ensure the highest reliability for mission-critical applications, remain highly cost competitive, and ensure a short time to market to meet tight design windows. IC manufacturers need a smarter approach to test not just to survive but to thrive. NI delivers smarter test solutions that scale from the lab to the production floor and meet the business needs of IC manufacturers.

A LETTER FROM THE CEO

Semiconductor test is a strategic focus area for NI, and we are privileged to work closely with many innovators in this industry. We understand that success in this industry means offering ICs that are always increasing in functionality, ensuring high quality, and competing with aggressive prices while fitting within tight market windows. This makes for a challenging and exciting market.

For NI to be a relevant and valuable test equipment vendor, we've needed to clearly understand the role that we can play to help our customers meet their business needs. We get a tremendous amount of feedback from our customers, and we witness a lot of frustration with the existing structure of the test equipment market. Customers want more competition from a viable vendor that has the capability, resources, and vision to think and invest long term. This vendor needs to disrupt the status quo by not only delivering superior technical capability but also taking a more holistic approach with an innovative business model.

Our open, software-centric platform delivers on this need in every aspect, and is supported by a vibrant ecosystem of developers and engineers to ensure customer success. With highly integrated modular hardware and flexible software in a compact form factor, customers can build and deploy test systems with R&D grade measurement quality that scale and meet the requirements of the production floor. And as test requirements change, solutions built on the NI platform can scale up in capability and adapt to new standards and protocols, ensuring the lowest total cost of ownership and shortest time to market.

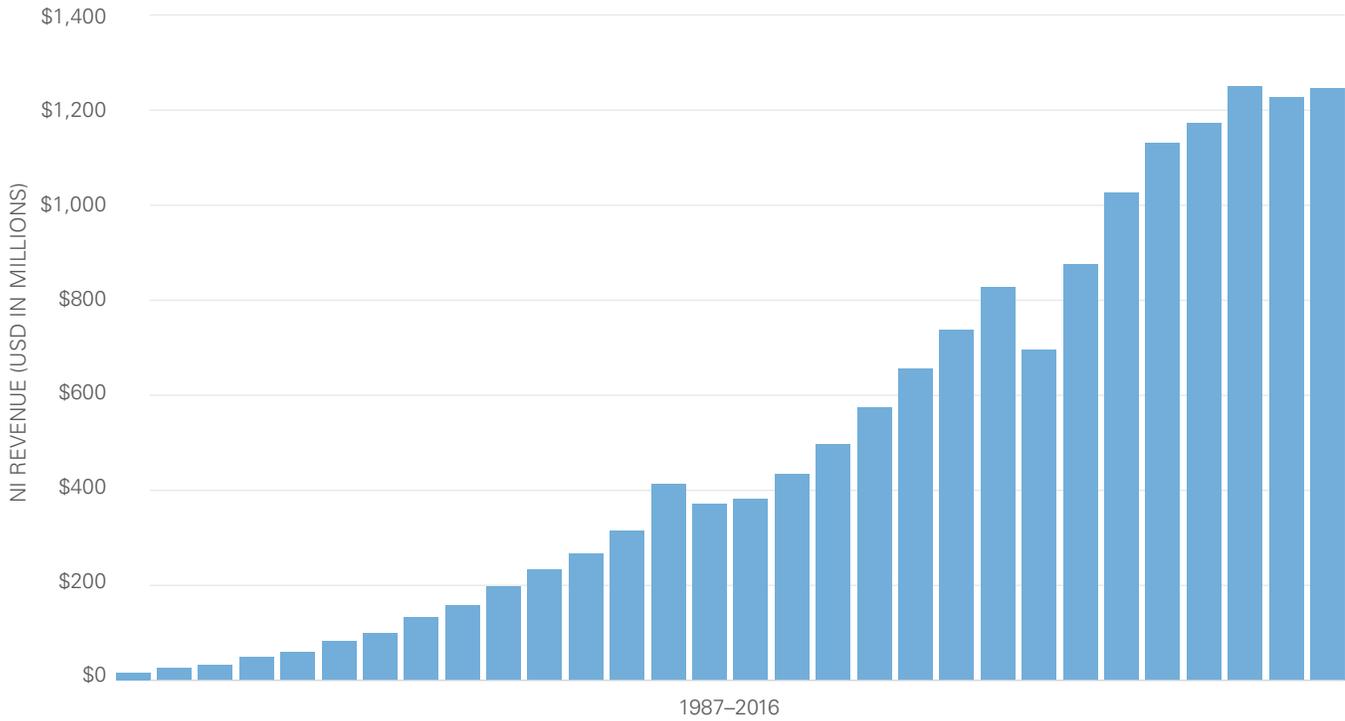
As we look to the future of the semiconductor industry, I could not be more excited. We are on the brink of the next generation of wireless communication, the IoT is growing in deployments every year, and autonomous vehicles are within reach. And as once disparate technologies continue to converge, our devices are growing smarter. The semiconductor industry plays a monumental role in realizing a better future encompassing all these elements. With NI's platform-based approach, technical capability, and consistent investment, we feel that we are in a unique position to partner with you in the semiconductor supply chain. I cannot think of a smarter approach to test than our platform.



A handwritten signature in black ink, appearing to read 'Alex Davern'. The signature is fluid and cursive, written over a light background.

Alex Davern
CEO

NI'S DIVERSIFIED PRODUCT PORTFOLIO ENABLES STEADY REVENUE GROWTH



NI'S DIVERSIFIED CUSTOMER PORTFOLIO ENABLES LONG-TERM INVESTMENT IN SEMICONDUCTOR

\$236 Million USD

Invested in R&D (in 2016)

1,400+

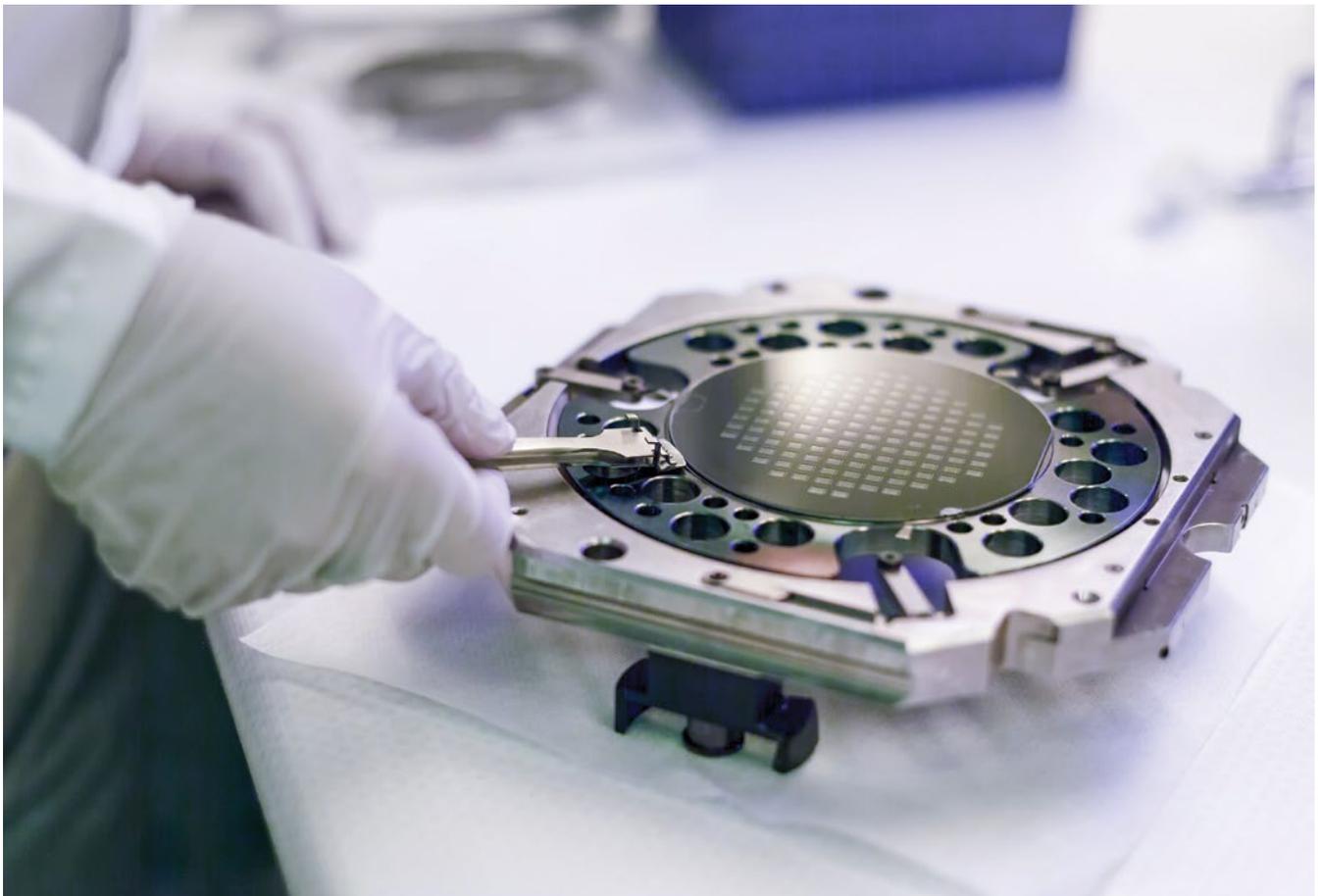
Sales and Support
Engineers Worldwide

2,100+

R&D Staff Worldwide

One Platform From Lab to Production

When ICs were simpler and less integrated, fixed-functionality box instruments were sufficient in the lab. But as test requirements grow with increased integration, so does the need for a broader mix of instrumentation. It is not uncommon to find a validation bench that is overflowing with instrumentation to the extent that floor and rack space becomes a limiting factor. But space isn't the only problem. Box instruments are optimized to work independently instead of together; integration over GPIB or Ethernet is not optimal for high data throughput, low latency communication, and tight synchronization.



Coverage Without Compromise

Use more than 1,500 instrument modules from DC to mmWave to customize your test system IO as needed by highly integrated ICs.

Data Correlation

Simplify the time-consuming task of data correlation by using the same high-performance, high-density instrumentation in your lab and production system.

Software Reuse

Save time by leveraging a common software framework and the test routines from R&D in your production test system.

On the other hand, production ATE is built primarily to meet the needs of highly integrated microprocessors, memory, and complex SOCs. But for RF and mixed-signal ICs, it struggles to scale, and often does not provide the right features. Overall, the traditional approach of box instruments in labs and ATEs in production is becoming a business risk for IC vendors. The inefficiencies range from the inability to reuse/leverage code modules to disjointed training and onboarding, resulting in a negative impact on both total cost and time to market. A new holistic approach, based on the platform of PXI and NI software, needs to be considered.



Small Footprint

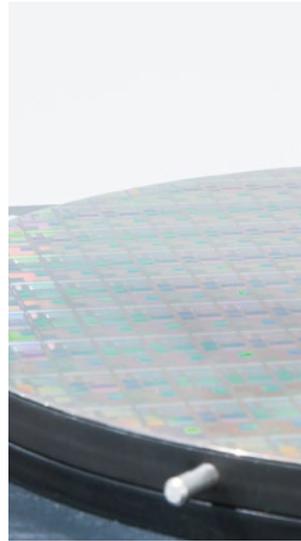
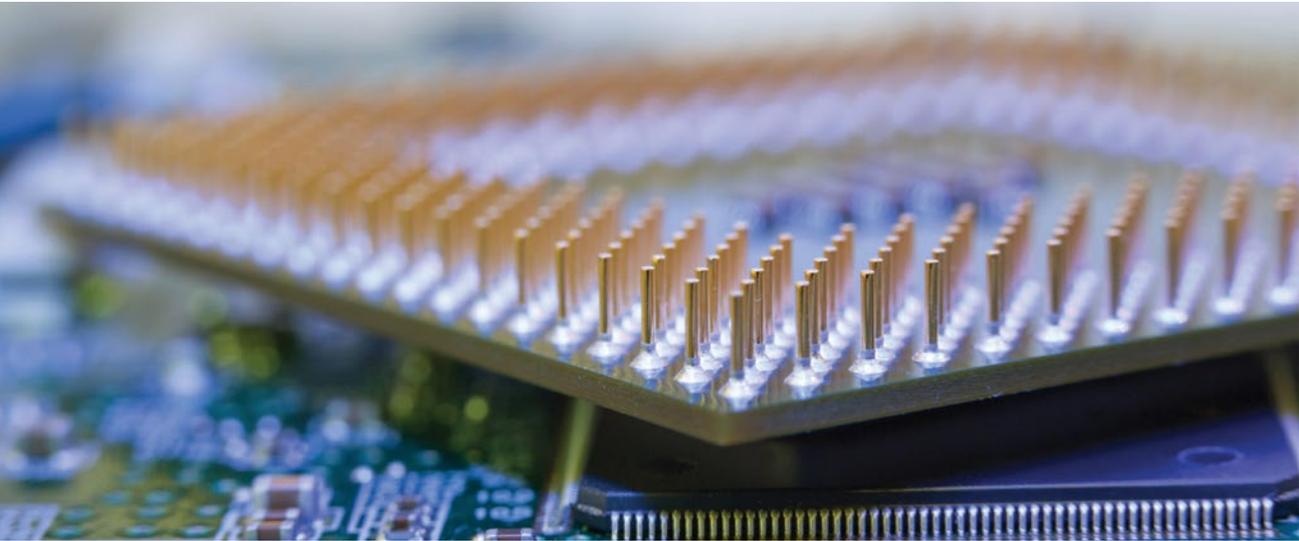
Take advantage of substantial power in a compact form factor with PXI, which has no knobs, dials, and buttons.

Automation

Harness the power of PXI's integrated timing and synchronization to fully automate tests and reduce test time.

Decreased Test Cost

Lower total cost of ownership with PXI's fast test times, excellent uptime, increased test coverage, and competitive capital cost.



Industry-Proven Customer Success

ON Semiconductor

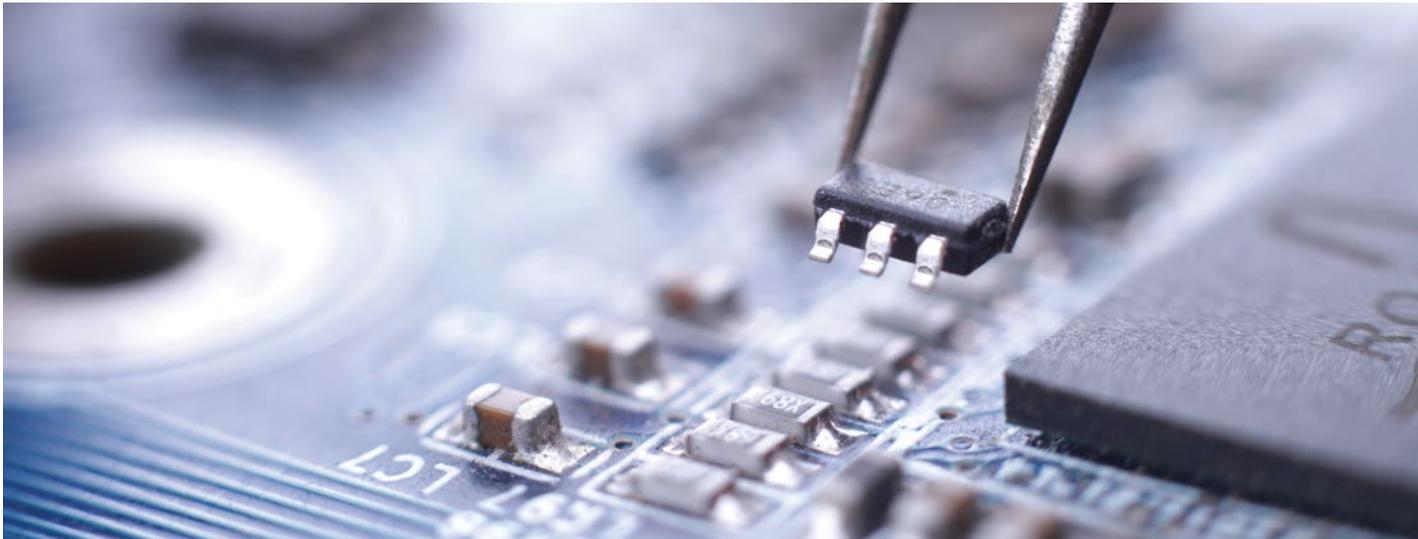
ON Semiconductor used the STS to develop a complete ATE test solution for high-end image sensors. This resulted in unprecedented test performance and flexibility for future requirements.

Infineon

Infineon deployed the STS for end-of-line test for mixed-signal devices. With optimal test coverage and a much lower price point, this solution outperformed traditional ATE.

Qualcomm

Qualcomm paired the software-designed NI PXI Vector Signal Transceiver (VST) with NI software to significantly increase test coverage. This also improved test speeds by more than 200X compared with traditional rack-and-stack instruments.



Intel

Intel used LabVIEW and the VST to more thoroughly test new features and corner cases for its latest RF transceivers. This increased product quality and saved several millions of dollars.

IDT

IDT deployed a next-generation production test system for its mixed-signal devices using the STS. The system's flexibility helped IDT reconfigure and grow as its performance needs increased.

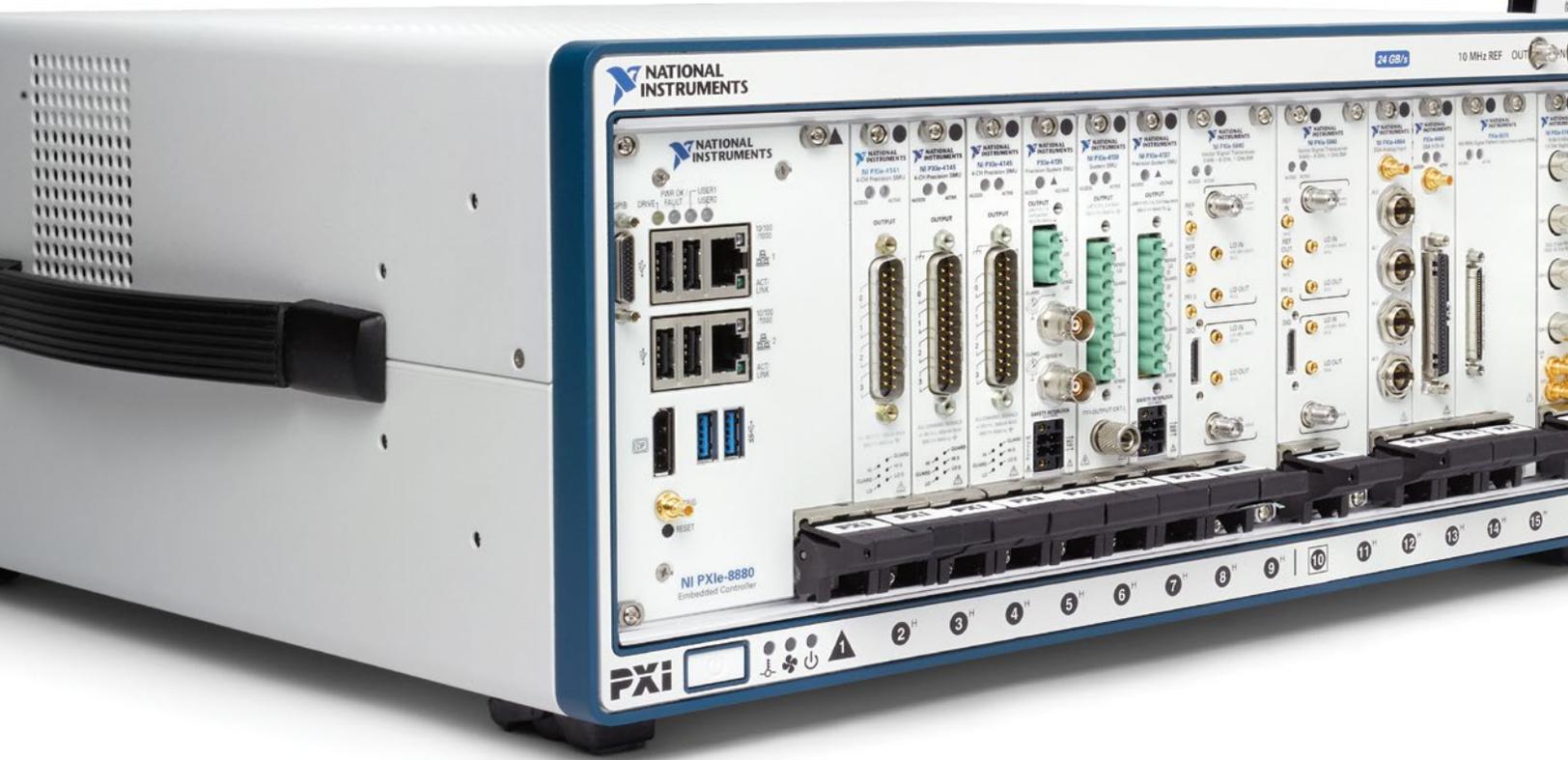
Broadcom

Broadcom used the VST to implement power serving on an FPGA level. This reduced the manufacturing test time of power amplifiers by 5X compared with existing test systems.

Foundation for Innovation

NI's approach to semiconductor test is based on a single underlying platform of PXI and software that you can use from the lab through production. With support from a vibrant ecosystem, this approach offers the openness you need to integrate third-party hardware and software as well as industry-specific mechanical enclosures and fixturing.

Adopted across multiple industries, PXI is an open platform founded in 1997 and governed by the PXI Systems Alliance with more than 1,500 products from 60 vendors. PXI chassis provide a high-speed, high-bandwidth PCI Express bus for data sharing and integrated timing and synchronization. PXI also offers a framework for using commercial off-the-shelf (COTS) technologies such as the latest multicore processors and FPGAs. To take advantage of the latest commercial computing power while meeting the long-term life-cycle requirements of industrial environments, the processors for PXI controllers are selected from Intel's embedded roadmap, which features controllers designed for long-term industrial use. This creates both a high-performance and low-cost deployment platform for semiconductor test from first silicon to final production test.



A System Powered by Software
Customize your test system with high-performance driver APIs optimized for the most popular application development environments such as NI LabVIEW or .NET.

Tightly Integrated Instrumentation
Perform complex multi-instrument routines seamlessly with multichassis synchronization options and the integrated timing and synchronization of the PXI backplane.

Higher Data Throughput
Stream up to 24 GB/s with subnanosecond latency through the latest PCI Express Gen 3 technology available on PXI Express chassis and controllers for data-intensive applications.



Parallel Test Execution

Rest assured that your system's controllers, with up to eight cores of Intel Xeon processing, have the horsepower to process as much as your tests demand without sacrificing efficiency.

Increased Measurement Coverage

Get the digital patterns, high-density source measure units, and high-performance RF measurements you need with PXI's breadth of class-leading instrumentation I/O.

Faster Measurement Times

Achieve best-in-class test times with technologies unique to NI, such as LabVIEW FPGA and advanced algorithms.

Semiconductor Test System (STS)

The STS series features fully production-ready test systems that pack NI technology in a form factor suitable for a semiconductor production test environment. The STS combines the NI PXI platform, TestStand test management software, and LabVIEW graphical programming inside a fully enclosed test head. Its “tester in a head” design houses all the key components of a production tester including system controllers; DC, AC, and RF instrumentation; device under test (DUT) interfacing; and device handler/prober docking mechanics. This compact design eliminates the extra floor space, power, and maintenance required by traditional ATE testers that unnecessarily increase the cost of test. Additionally, with the open, modular STS design, you can take advantage of the latest industry-standard PXI modules for more instrumentation and computing power.



STS Services and Support

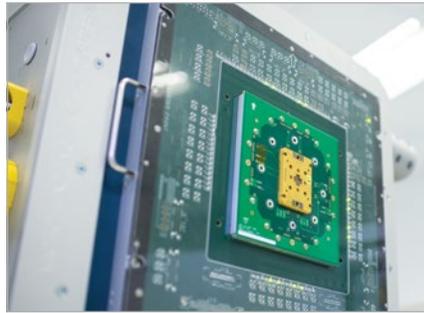
NI offers specialized service programs for the STS designed to meet the critical uptime needs of semiconductor customers. In addition to standard NI services and support, STS customers have access to:

- On-site setup included with every first STS system deployment
- 24x7 technical support by phone, by email, or on-site
- On-site engineering support
- STS calibration services
- Repair coverage and express delivery of replacement parts



RF Instruments

NI's RF portfolio includes the industry-leading VST supported by a multiport RF subsystem in the STS that is highly configurable for a variety of RFIC test needs.



Standard Docking/Interface

The STS docking and interfacing infrastructure allows for seamless integration with both device handlers for package test and wafer probers, making it ready for any production test cell.



Robust Test Head

With a compact form factor and a ruggedized frame, the STS's "tester in a head" design houses all the key components of a production tester including system controllers.



Mixed-Signal and DC Instruments

NI has a comprehensive portfolio of source measure units (DC), digital pattern instruments, dynamic signal analyzers, arbitrary waveform generators, and oscilloscopes for a variety of mixed-signal test needs.



Maintenance Software

The STS's intuitive graphical user interface allows for quick troubleshooting, monitoring, and system-level debugging to ensure high uptime and reliability when you deploy the STS to the manufacturing floor.



System Calibration

The STS offers system-level DC, digital, and RF tools to calibrate to the spring probe interface or RF blind mates, saving valuable time and ensuring the highest possible system-level measurement quality.

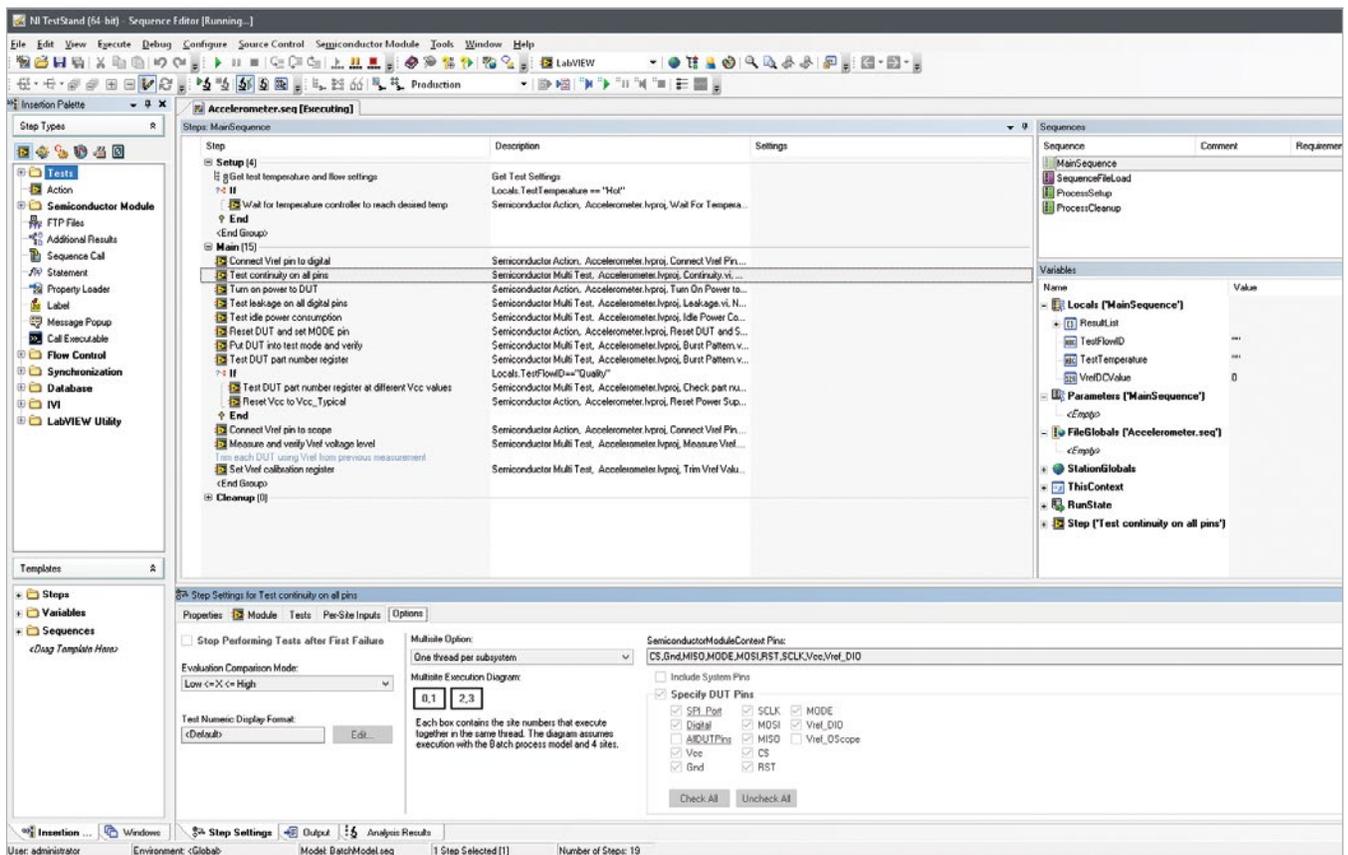
"As integrated circuit complexity grows exponentially, cost-effective ATE that provides optimal test coverage in applications from design verification to end-of-line production test is increasingly important. For mixed-signal test, the PXI-based STS outperforms what we typically see in traditional ATE with optimal test coverage at a very low cost."

Dr. Hans-Peter Kreuter, Infineon

Software That Scales

Test Management Software

Extend the off-the-shelf functionality of TestStand, the industry-standard test management software, with the TestStand Semiconductor Module to quickly develop, debug, and deploy characterization and production test programs. The same software framework that powers the STS serves as the backbone of PXI test systems in characterization, making a seamless path for scaling your efforts and IP from the lab to production. Designed for both wafer-level and final package test applications, the software framework offers features including pin/channel mapping (for pin-based programming), binning, handler/prober drivers, limit importing/exporting, and multisite programming.



Sequence Editor

The TestStand Sequence Editor supports code modules developed in LabVIEW or .NET, so you can develop and debug complex DUT test sequences. Set break points, step in and out of modules, and pinpoint bottlenecks.

Parallel Test

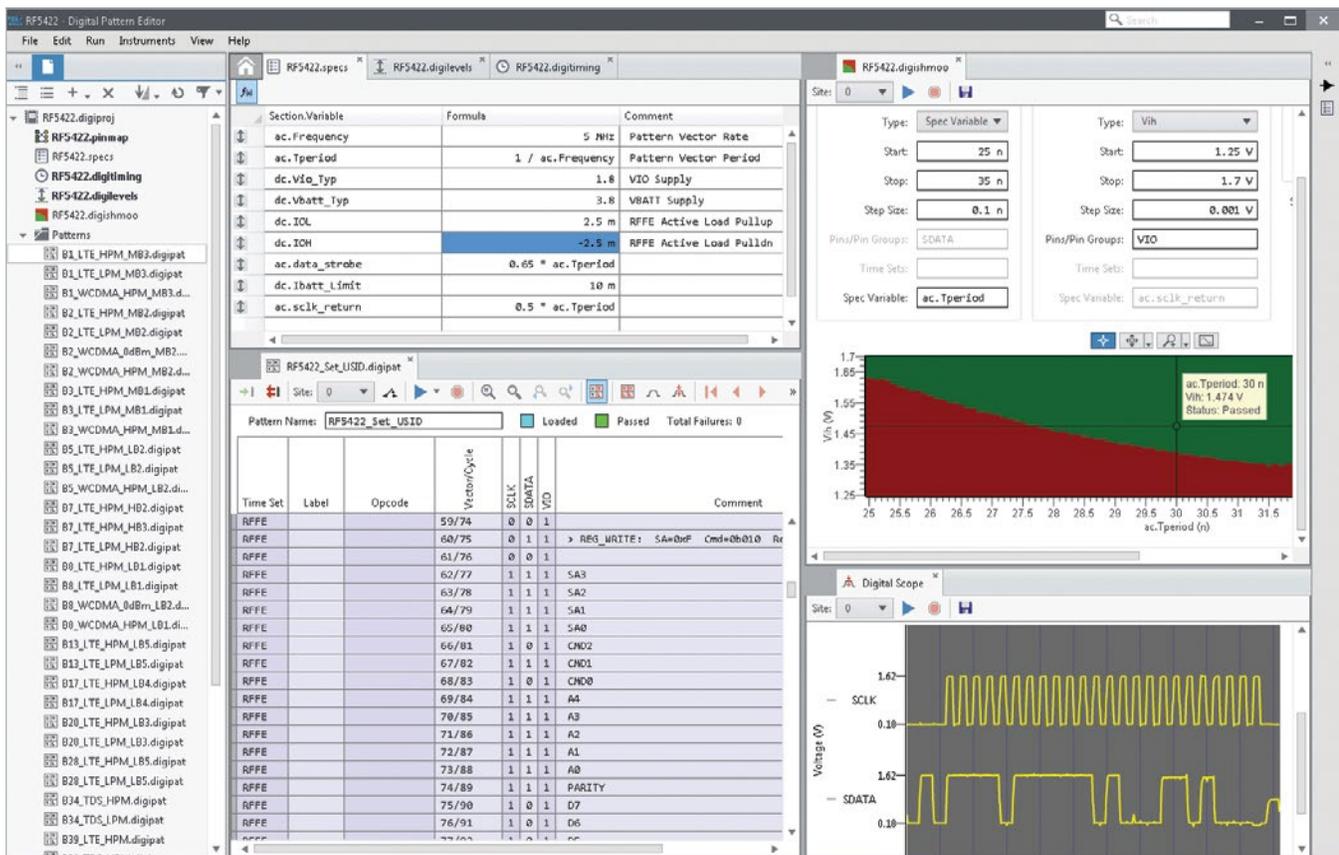
TestStand's parallel processing engine unlocks the potential of the latest multicore processing technologies, making multisite test programs execute with an unprecedented level of efficiency and performance.

DUT-Centric Paradigm

You can create multisite test programs that seamlessly execute with a variable number of sites by developing channel maps to instruments.

Interactive, Out-of-the-Box Software

The Digital Pattern Editor is an interactive tool for importing, editing, debugging, and bursting test patterns. The editor includes tools like Shmoo plots to provide a deeper understanding of DUT performance across variation. You also can use rich debugging features to overlay pattern failures on a pattern or use the digital scope tool to view the pin data. With integrated editing sheets for device pin maps, specifications, and patterns, you can develop or edit imported digital test vectors and patterns.



Device Specifications

All devices have, or need, specifications that define how they can be used. A test engineer can define these specifications and use them as variables in formulas throughout the Digital Pattern Editor.

Digital Scope Tool

The tool features a progressively updated two-dimensional plot of the actual analog levels of the digital waveform using the pattern, timing set, and level.

Shmoo Tool

The Shmoo tool provides a dynamically updated intensity plot of pass and fail values for a sweep of two variables including levels, voltages, currents, edges, or specifications at a time.



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NI Services and Support

Hardware Services

Fix maintenance costs, improve uptime, and maintain traceability starting at only a fraction of the hardware price with NI service programs.

Training and Certification

Develop 50 percent faster and spend 43 percent less time on code maintenance with NI training courses. Also validate your expertise with NI certifications.

Technical Support

Get started with NI products faster or troubleshoot tough issues by contacting NI applications engineers who are ready to help via phone and email.

Consultation and Integration

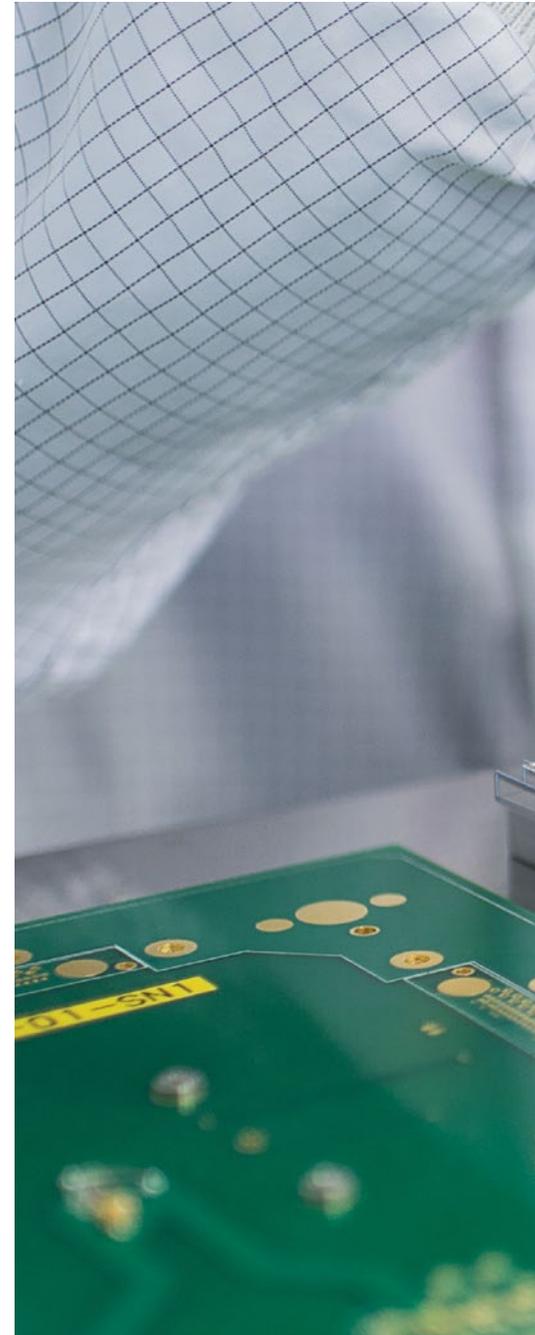
Leverage our extensive network of Alliance Partners and NI systems engineers for assistance with prototyping, feasibility analysis, consulting, and systems integration.

Software License Programs

Streamline NI software management by accessing multiple levels of training, technical support, and tools through your software license.

Technical Resources

Access volumes of self-help information at ni.com including application tips, example programs, and developer communities.



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